

TOSHIBA PHOTOCOUPLER

TLP3009(D4)SERIES

ATTACHMENT : SPECIFICATIONS FOR VDE0884 OPTION: (D4)

Types : TLP3009, TLP3010, TLP3011, TLP3012 TLP3020, TLP3021, TLP3022, TLP3023
 TLP3031, TLP3032, TLP3033 TLP3041, TLP3042, TLP3043
 TLP3051, TLP3052 TLP3061, TLP3062, TLP3063

Type designations for 'Option: (D4)', which are tested under VDE0884 requirements.



Ex. : TLP3063 (D4-LF2) D4 : VDE0884 option
 LF2 : lead bend

Note: Use Toshiba standard type number for safety standard application.
 Ex. TLP3063(D4-LF2) → TLP3063

VDE0884 ISOLATION CHARACTERISTICS

DESCRIPTION	SYMBOL	RATING	UNIT
Application Classification (DIN VDE0109 12.83, Table 1) for rated mains voltage ≤ 300 V _{RMS} for rated mains voltage ≤ 600 V _{RMS}		I- IV I- III	—
Climatic Classification (DIN IEC68 Teil 1 / 09.80)		55 / 100 / 21	—
Pollution Degree (DIN VDE0109 / 12.83)		2	—
Maximum Operating Insulation Voltage	V _{IORM}	630	Vpk
Input to output Test Voltage, Method A V _{pr} =1.2 × V _{IORM} , Type and Sample Test t _p = 60s, Partial Discharge < 5pC	V _{pr}	760	Vpk
Input to output Test Voltage, Method B V _{pr} = 1.6 × V _{IORM} , 100% Production Test t _p = 1s, Partial Discharge < 5pC	V _{pr}	1000	Vpk
Highest Permissible Overvoltage (Transient Overvoltage, t _{pr} = 10s)	V _{TR}	6000	Vpk
Safety Limiting Values (Max. permissible ratings in case of fault, also refer to thermal derating curve Current (Input current I _F , Psi = 0) Power (Output or Total Power Dissipation) Temperature	I _{si} P _{si} T _{si}	400 700 150	mA mW °C
Insulation Resistance at T _{si} , V _{IO} = 500V	R _{si}	≥10 ⁹	Ω

INSULATION RELATED SPECIFICATIONS

		 7.62 mm pitch standard type	 10.16 mm pitch (LF2 type)
Minimum Creepage Distance*	Cr	7.0 mm	8.0 mm
Minimum Clearance*	Cl	7.0 mm	8.0 mm
Minimum Insulation Thickness	ti	0.5 mm	
Comperative Tracking Index (DIN IEC112 / VDE0303, Part 1)	CTI	175 (VDE0109 / 12.83 Group IIIa)	

*: in accordance with DIN VDE0109 12.83, Table 2, & 4)

1. If a printed circuit is incorporated, the creepage distance and clearance may be reduced below this value (e. g. at a standard distance between soldering eye centres of 7.5mm). If this is not permissible, the user shall take suitable measures.
2. This photocoupler is suitable for 'safe electrical isolation' only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.

VDE Test sign : Marking on product for VDE0884 :



Marking on packing for VDE0884 :



0884

Figure 1 Partial discharge measurement procedure according to VDE0884
Destructive test for qualification and sampling tests.

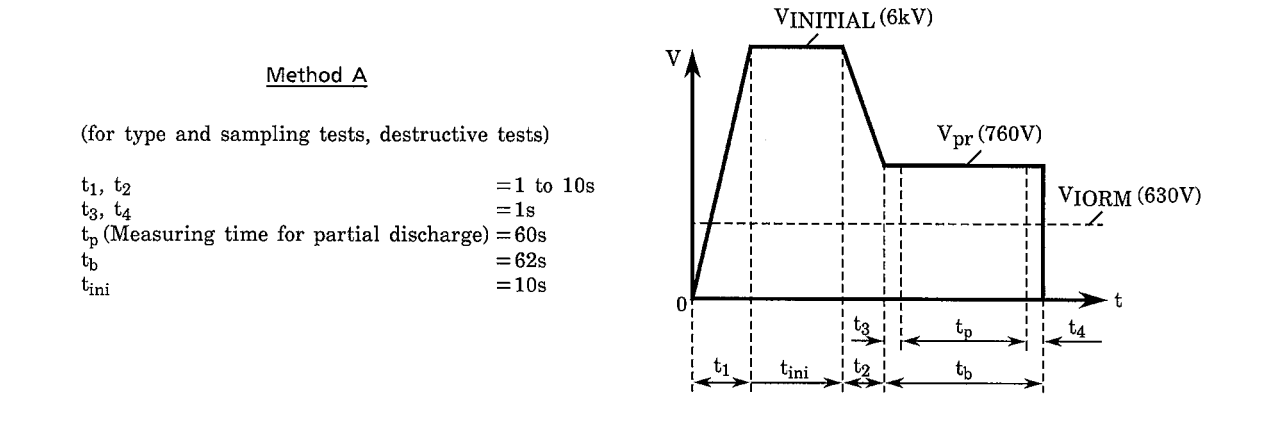


Figure 2 Partial discharge measurement procedure according to VDE0884
Non-destructive test for 100% inspection.

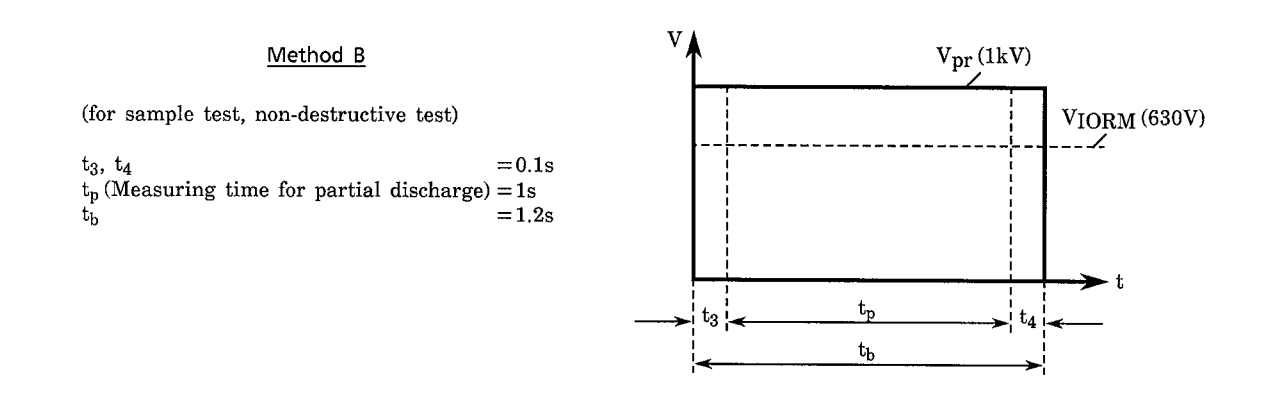
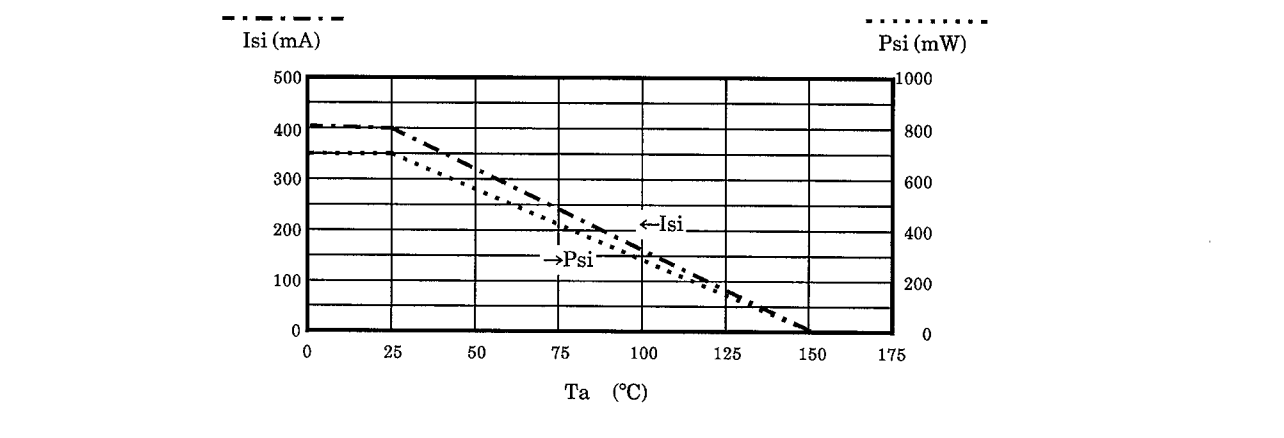


Figure 3 Dependency of maximum safety ratings on ambient temperature



RESTRICTIONS ON PRODUCT USE

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In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
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